

AUG 09 2002

PATENT & TRADEMARK OFFICE

Atty. Docket No. 1074D2	Serial No. 10/075,021
LIST OF CITATIONS BY APPLICANT (Use several sheets if necessary)	Applicant James J. Finley et al.
	Filing Date February 12, 2002 Group 1775

U.S. PATENT DOCUMENTS

Exam. Init.		Document No.	Date	Name	Class	Subclass	Filing Date if appropriate
ATP	AA	3,655,545	4/72	Gillery et al.	204	192	
	AB	3,962,488	6/76	Gillary	204	192	RECEIVED TECHNOLOGY CENTER 15-APR-2003
	AC	4,194,022	3/80	Gillary	427	109	RECEIVED TECHNOLOGY CENTER 15-APR-2003
	AD	4,716,086	12/87	Gillery et al.	428	630	RECEIVED TECHNOLOGY CENTER 15-APR-2003
	AE	4,717,632	1/88	Keem et al.	428	698	RECEIVED TECHNOLOGY CENTER 15-APR-2003
	AF	4,786,563	11/88	Gillary et al.	428	630	RECEIVED TECHNOLOGY CENTER 15-APR-2003
	AG	4,806,220	2/89	Finley	204	192.27	RECEIVED TECHNOLOGY CENTER 15-APR-2003
	AH	4,898,789	2/90	Finley	428	623	RECEIVED TECHNOLOGY CENTER 15-APR-2003
	AI	4,898,790	2/90	Finley	428	623	RECEIVED TECHNOLOGY CENTER 15-APR-2003
↓	AJ	5,028,759	7/91	Finley	219	203	
ATP	AK	5,059,295	10/91	Finley	204	192.27	

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Subclass	Translation Yes No
ATP	AL	2,178,064	2/87	Great Britain			
ATP	AM	0 354 391	2/90	EPO			

OTHER CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)

ATP	AR	Inoue et al., Materials Letters 16 (1993) pp. 181-184, "Nitrogen-induced amorphization in Al ₈₀ Ti ₂₀ films prepared by reactive sputtering"
ATP	AS	Geraghty, K. G. et al., "Kinetics of the Reactive Sputter Deposition of Titanium Oxides", JOURNAL OF THE ELECTROCHEMICAL SOCIETY, Aug. 1976, Vol. 123, Nr. 8, Pages 1201-1207
ATP	AT	Yoshitake, M. et al., "The Use of Ion Beam Current as a Process Control in the Reactive Sputtering of Zirconium Oxide", THIN SOLID FILMS, 15 July 1993, Vol. 230, Nr. 1, Pages 48-54

Examiner	Date Considered
<i>G. J.</i>	1/26/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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ATP	AA	5,062,937	11/91	Komuro	204	192.15	
	AB	5,073,451	12/91	Iida et al.	428	336	
	AC	5,087,340	2/92	Onagi et al.	204	192.2	
	AD	5,110,637	5/92	Ando et al.	204	192.16	
	AE	5,128,214	7/92	Takayanagi et al.	428	681	
	AF	5,209,835	5/93	Makino et al.	204	192.16	
	AG	5,270,517	12/93	Finley	219	203	
	AH	5,292,417	3/94	Kugler	204	192.13	
	AI	5,302,449	4/94	Eby et al.	428	336	
↓	AJ	5,302,461	4/94	Anthony	428	472	
ATP	AK	5,318,685	6/94	O'Shaughnessy	204	192.27	

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	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						

OTHER CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)

ATP	AR	U.S. Patent Application Serial No. 08/151,229 filed November 12, 1993.
	AS	
	AT	

Examiner <i>J. P.</i>	Date Considered <i>1/29/03</i>
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ATP	AA	5,332,618	7/94	Austin	428	216	
	AB	4,522,844	6/85	Khanna et al.	204	192.11	
	AC	4,696,731	9/87	Tenhover	204	192.15	TECHNOLOGY CENTER 192
	AD	5,078,846	1/92	Miller et al.	204	192.15	RECEIVED FEB 13 2002
	AE	5,108,846	4/92	Steininger	204	192.15	
↓	AF	5,110,662	5/92	Depauw et al.	204	192.26	
ATP	AG	6,346,174	2/02	Finley et al.	204	192.15	
	AH						
	AI						
	AJ						
	AK						

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